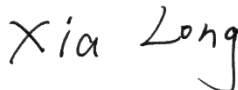


TEST REPORT

Applicant: MeiG Smart Technology Co., Ltd
Address: 2nd Floor, Office Building, No.5 Lingxia Road,
Fenghuang, Fuyong Street, Bao'an District,
Shenzhen, China.
Equipment Type: Smart Module
Model Name: SLM500SA
Brand Name: MEIGLink
FCC ID: 2APJ4-SLM500SA
Test Standard: 47 CFR Part 15 Subpart B
ANSI C63.4-2014
Sample Arrival Date: May 16, 2023
Test Date: May 23, 2023 ~ May 24, 2023
Date of Issue: Jun. 19, 2023

ISSUED BY:

Shenzhen BALUN Technology Co., Ltd.

Tested by: Fei Liu**Checked by:** Xia Long**Approved by:** Liao Jianming
(Technical Director)

Revision History

Version	Issue Date	Revisions
<u>Rev. 01</u>	<u>Jun. 19, 2023</u>	<u>Initial Issue</u>

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1 GENERAL INFORMATION

1.1 Test Laboratory

Name	Shenzhen BALUN Technology Co., Ltd.
Address	Block B, 1/F, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
Phone Number	+86 755 6685 0100

1.2 Test Location

Name	Shenzhen BALUN Technology Co., Ltd.
Location	☒ Block B, 1/F, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China
	☐ 1/F, Building B, Ganghongji High-tech Intelligent Industrial Park, No. 1008, Songbai Road, Yangguang Community, Xili Sub-district, Nanshan District, Shenzhen, Guangdong Province, P. R. China
Accreditation Certificate	The laboratory is a testing organization accredited by FCC as a accredited testing laboratory. The designation number is CN1196.

2 PRODUCT INFORMATION

2.1 Applicant Information

Applicant	MeiG Smart Technology Co., Ltd
Address	2nd Floor, Office Building, No.5 Lingxia Road, Fenghuang, Fuyong Street, Bao'an District, Shenzhen, China.

2.2 Manufacturer Information

Manufacturer	MeiG Smart Technology Co., Ltd
Address	2nd Floor, Office Building, No.5 Lingxia Road, Fenghuang, Fuyong Street, Bao'an District, Shenzhen, China.

2.3 Factory Information

Factory	N/A
Address	N/A

2.4 General Description for Equipment under Test (EUT)

EUT Name	Smart Module
Model Name Under Test	SLM500SA
Series Model Name	N/A
Description of Model name differentiation	N/A
Hardware Version	V1.01
Software Version	T04
Dimensions (Approx.)	N/A
Weight (Approx.)	N/A

2.5 Ancillary Equipment

Note: Not Applicable.

2.6 Technical Information

Network and Wireless connectivity	2G Network GSM 850/900/1800/1900MHz 3G Network WCDMA Band 2/4/5/8 4G Network FDD LTE Band 2/4/5/7/8/28 LTE TDD Band 34/38/39/41 Bluetooth (BR+EDR+BLE) WIFI 802.11b, 802.11g, 802.11n GPS, GLONASS, BDS
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The requirement for the following technical information of the EUT was tested in this report:

The Highest Speed of Processor	N/A
--------------------------------	-----

3 SUMMARY OF TEST RESULTS

3.1 Test Standards

No.	Identity	Document Title
1	47 CFR Part 15 Subpart B	Unintentional Radiators
2	ANSI C63.4-2014	American National Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz

3.2 Verdict

No.	Description	FCC Rule	Test Verdict	Result
1	Radiated Emission	15.109	Pass	Annex A .1
2	Conducted Emission, AC Ports	15.107	Pass	Annex A .2

3.3 Test Uncertainty

The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Measurement	Value
Conducted emissions (9 kHz-30 MHz)	3.22 dB
Radiated emissions (30 MHz-1 GHz)-10m	4.80 dB
Radiated emissions (30 MHz-1 GHz)-3m	4.76 dB
Radiated emissions (1 GHz-18 GHz)-3m	4.88 dB

4 GENERAL TEST CONFIGURATIONS

4.1 Test Environments, Test Date and Test Engineer

Test items	Voltage	Temperature	Relative Humidity	Ambient Pressure	Test Date	Test Engineer
Radiated Emission	DC 3.8V	24.7℃	52%RH	101kPa	May 23, 2023	Liang Yongming
	DC 3.8V	23.2℃	56%RH		May 24, 2023	Tian Shuo
Conducted Emission	DC 3.8V	22.6℃	63%RH		May 23, 2023	Yang Yang

4.2 Test Equipment List

Radiated Emission Test For Frequency Below 1 GHz (10 m)						
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use
EMI Receiver	ROHDE&SCHWARZ	ESRP	101036	2022.09.09	2023.09.08	☒
Amplifier (30-1GHz)	COM-MV	ZT30-1000M	B2018054558	2022.12.07	2023.12.06	☒
Test Antenna-Bi-Log	SCHWARZBECK	VULB 9168	9168-01162	2020.08.12	2023.08.11	☒
Anechoic Chamber	EMC Electronic Co., Ltd	20.10*11.60*7.35m	N/A	2021.08.15	2024.08.14	☒
Description	Manufacturer	Name		Version		Use
Test Software	BALUN	BL410-E		V22.930		☒

Radiated Emission Test For Frequency Above 1 GHz (3m)						
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use
EMI Receiver	KEYSIGHT	N9038A	MY53220118	2022.09.08	2023.09.07	☒
Spectrum Analyzer	ROHDE & SCHWARZ	FSV40	101544	2022.12.07	2023.12.06	☒
Amplifier (1-12GHz)	COM-MV	DLNAB-1000-12000-002	18080279	2022.12.07	2023.12.06	☒
Amplifier (0.8-21GHz)	Mini-Circuits	ZVA-213-S+	619201336	2022.04.12	2025.04.11	☒
Amplifier (18-40GHz)	COM-MV	KA_LNA18-40G-01	18050001	2021.07.02	2024.07.01	☒
Test Antenna-Horn	SCHWARZBECK	BBHA 9120D	1148	2022.04.12	2025.04.11	☒
Test Antenna-Horn	A-INFOMW	LB-180400KF	J211060273	2021.07.02	2024.07.01	☒
Anechoic Chamber	ChangNing	9m*6m*6m	101	2023.03.26	2026.03.03	☒
Description	Manufacturer	Name		Version		Use
Test Software	BALUN	BL410-E		V22.930		☒

Conducted disturbance Test						
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use
EMI Receiver	KEYSIGHT	N9010B	MY57110309	2022.09.09	2023.09.08	☒
LISN	SCHWARZBECK	NSLK 8127	8127-687	2023.05.16	2024.05.15	☒
Shielded Room	YiHeng Electronic Co., Ltd	3.5m*3.1m*2.8m	112	2022.02.19	2025.02.18	☒
Description	Manufacturer	Name		Version		Use
Test Software	BALUN	BL410-E		V22.930		☒

4.3 Test Enclosure list

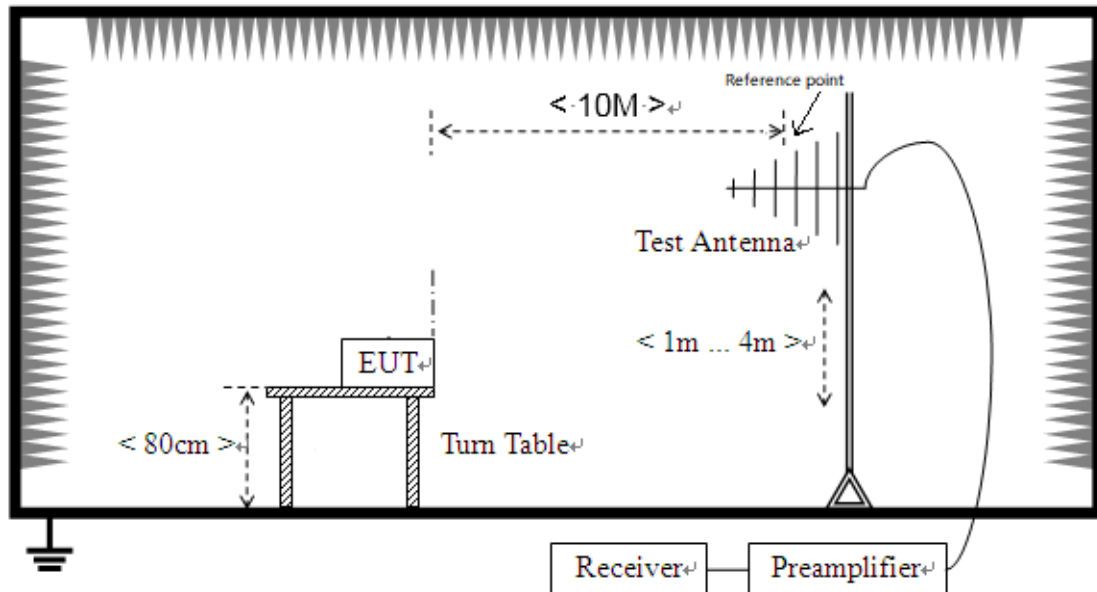
Description	Manufacturer	Model	Serial No.	Length	Description	Use
RF Cable	N/A	N/A	N/A	N/A	N/A	☒
Antenna	N/A	N/A	N/A	N/A	N/A	☒
EVB Board	N/A	N/A	N/A	N/A	N/A	☒
Screen	N/A	N/A	N/A	N/A	N/A	☒
DC Source	ITECH	IT6873A	N/A	N/A	N/A	☒

4.4 Test Configurations

Test Configuration s (TC) No.	Description
TC01	<u>The GSM 850 MHz Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + GSM 850 MHz Rx
TC02	<u>The GSM 900 MHz Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + GSM 900 MHz Rx
TC03	<u>The GSM 1800 MHz Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + GSM 1800 MHz Rx
TC04	<u>The GSM 1900 MHz Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + GSM 1900 MHz Rx
TC05	<u>The WCDMA B2 Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + WCDMA B2 Rx
TC06	<u>The WCDMA B4 Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + WCDMA B4 Rx
TC07	<u>The WCDMA B5 Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + WCDMA B5 Rx
TC08	<u>The WCDMA B8 Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + WCDMA B8 Rx
TC09	<u>The LTE B2 Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + LTE B2 Rx
TC10	<u>The LTE B4 Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + LTE B4 Rx
TC11	<u>The LTE B5 Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + LTE B5 Rx
TC12	<u>The LTE B7 Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + LTE B7 Rx
TC13	<u>The LTE B8 Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + LTE B8 Rx
TC14	<u>The LTE B28 Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + LTE B28 Rx
TC15	<u>The LTE B34 Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + LTE B34 Rx
TC16	<u>The LTE B38 Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + LTE B38 Rx
TC17	<u>The LTE B39 Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + LTE B39 Rx
TC18	<u>The LTE B40 Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + LTE B40 Rx
TC19	<u>The LTE B41 Rx Test Mode</u> EUT + RF Cable + Antenna + EVB Board + Screen + DC Source + LTE B41 Rx

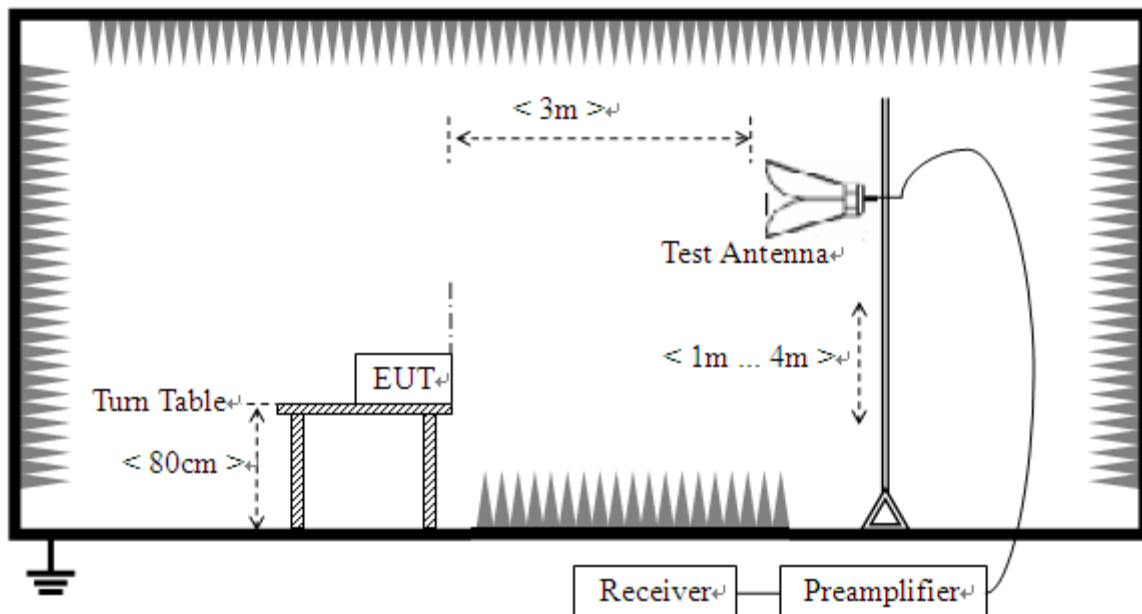
4.5 Test Setups

Test Setup 1

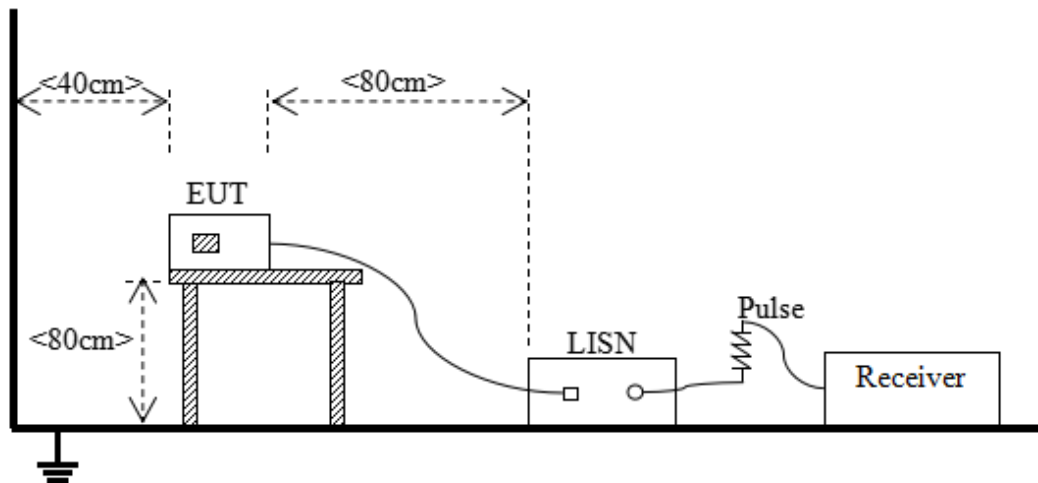


(For Radiated Emission Test (30 MHz-1 GHz))

Test Setup 2



(For Radiated Emission Test (above 1 GHz))

Test Setup 3

(For Conducted Emission, AC Ports Test)

4.6 Test Conditions

Test Case	Test Conditions	
Radiated Emission	Test Setup	Test Setup 1&2
	Test Configuration	TC01~TC19 ^{Note}
Conducted Emission, AC Ports	Test Setup	Test Setup 3
	Test Configuration	TC01~TC19 ^{Note}
Note: Based on client request, all normal using modes of the normal function were tested but only the worst test data of the worst mode is reported by this report. The GSM 850 Test Mode is the worst mode in this report.		

5 TEST ITEMS

5.1 Emission Tests

5.1.1 Radiated Emission

5.1.1.1 Limit

Frequency range (MHz)	Class B (at 3 m)		Class B (at 10 m)	Class A (at 10 m)	
	Field Strength ($\mu\text{V/m}$)	Field Strength (dB $\mu\text{V/m}$)	Field Strength (dB $\mu\text{V/m}$)	Field Strength ($\mu\text{V/m}$)	Field Strength (dB $\mu\text{V/m}$)
30 - 88	100	40	30	90	39
88 - 216	150	43.5	33.5	150	43.5
216 - 960	200	46	36	210	46.4
Above 960	500	54	44	300	49.5

NOTE:

- 1) Field Strength (dB $\mu\text{V/m}$) = $20 \cdot \log [\text{Field Strength } (\mu\text{V/m})]$.
- 2) In the emission tables above, the tighter limit applies at the band edges.

5.1.1.2 Test Setup

Refer to 4.5 section (test setup 1 to test setup 2) for radiated emission test, the photo of test setup please refer to ANNEX B.

5.1.1.3 Test Procedure

All Spurious Emission tests were performed in X, Y, Z axis direction. And only the worst axis test condition was recorded in this test report.

An initial pre-scan was performed in the chamber using the EMI Receiver in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by Bi-Log antenna with 2 orthogonal polarities.

The measurement frequency range is from 30 MHz to the 5th harmonic of the maximum frequency of the EUT internal source. The Turn Table is actuated to turn from 0° to 360°, and both horizontal and vertical polarizations of the Test Antenna are used to find the maximum radiated power. Mid channels on all channel bandwidth verified. Only the worst RB size/offset presented.

Use the following spectrum analyzer settings:

Span = wide enough to fully capture the emission being measured

RBW = 1 MHz for $f \geq 1 \text{ GHz}$, 100 kHz for $f < 1 \text{ GHz}$

VBW $\geq$ RBW

Sweep = auto

Detector function = peak for $f < 1 \text{ GHz}$, peak & RMS Average for $f \geq 1 \text{ GHz}$

Trace = max hold

5.1.1.4 Test Result

Please refer to ANNEX A.1.

NOTE:

1. Results (dB μ V/m) = Reading (dB μ V/m) + Factor (dB/m)

The reading level is calculated by software which is not shown in the sheet

2. Factor (dB/m) = Antenna Factor (dB/m) + Cable Factor (dB) – Amplifier Gain (dB)

3. Over limit = Results – Limit.

5.1.2 Conducted Emission

5.1.2.1 Test Limit

Frequency range (MHz)	Class A	
	Quasi-peak (dB μ V)	Average (dB μ V)
0.15 - 0.50	79	66
0.50 - 30	73	60

Frequency range (MHz)	Class B	
	Quasi-peak (dB μ V)	Average (dB μ V)
0.15 - 0.50	66 to 56	56 to 46
0.50 - 5	56	46
5 - 30	60	50

NOTE:

- 1) The lower limit shall apply at the band edges.
- 2) The limit decreases linearly with the logarithm of the frequency in the range 0.15 - 0.50 MHz.

5.1.2.2 Test Setup

Refer to 4.5 section test (test setup 3) for conducted emission, the photo of test setup please refer to ANNEX B.

5.1.2.3 Test Procedure

The EUT is connected to the power mains through a LISN which provides 50 Ω /50 μ H of coupling impedance for the measuring instrument. The test frequency range is from 150 kHz to 30 MHz. The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels that are more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed.

Devices subject to Part 15 must be tested for all available U.S. voltages and frequencies (such as a nominal 120 VAC, 50/60 Hz and 240 VAC, 50/60 Hz) for which the device is capable of operation. A device rated for 50/60 Hz operation need not be tested at both frequencies provided the radiated and line conducted emissions are the same at both frequencies.

Use the following spectrum analyzer settings:

RBW = 9 kHz

VBW $\geq$ RBW

Sweep = 10ms

Detector function = peak & Average

Trace = max hold

5.1.2.4 Test Result

Please refer to ANNEX A.2.

NOTE:

1. Results (dBμV) = Reading (dBμV) + Factor (dB)

The reading level is calculated by software which is not shown in the sheet

2. Factor = Insertion loss + Cable loss

3. Over limit = Results – Limit.

ANNEX A TEST RESULTS

A.1 Radiated Emission

Note 1: The symbol of “--” in the table which means not application.

Note 2: For the test data above 1 GHz, according the ANSI C63.4-2014, where limits are specified for both average and peak (or quasi-peak) detector functions, if the peak (or quasi-peak) measured value complies with the average limit, it is unnecessary to perform an average measurement.

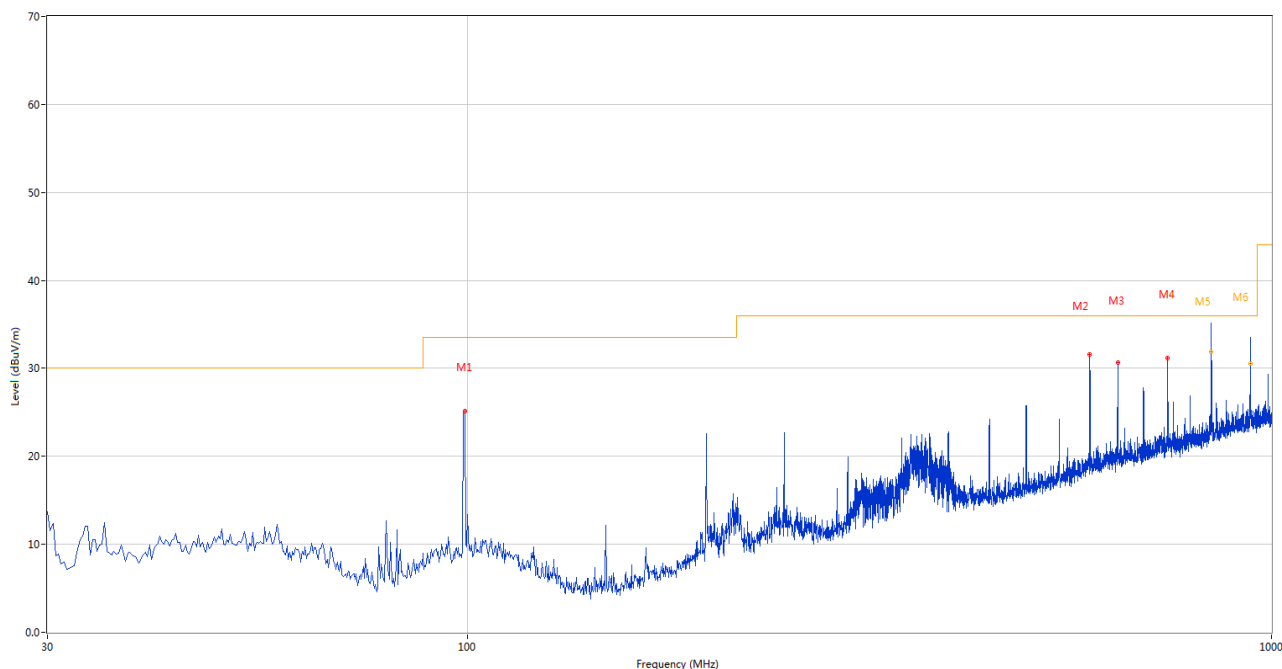
Note 3: The Radiated Emission from 18G-40G is noise only, do not show on the report.

Note 4: All the configurations were pre tested, only the worst configuration has been reported in this report.

Test Data and Plots

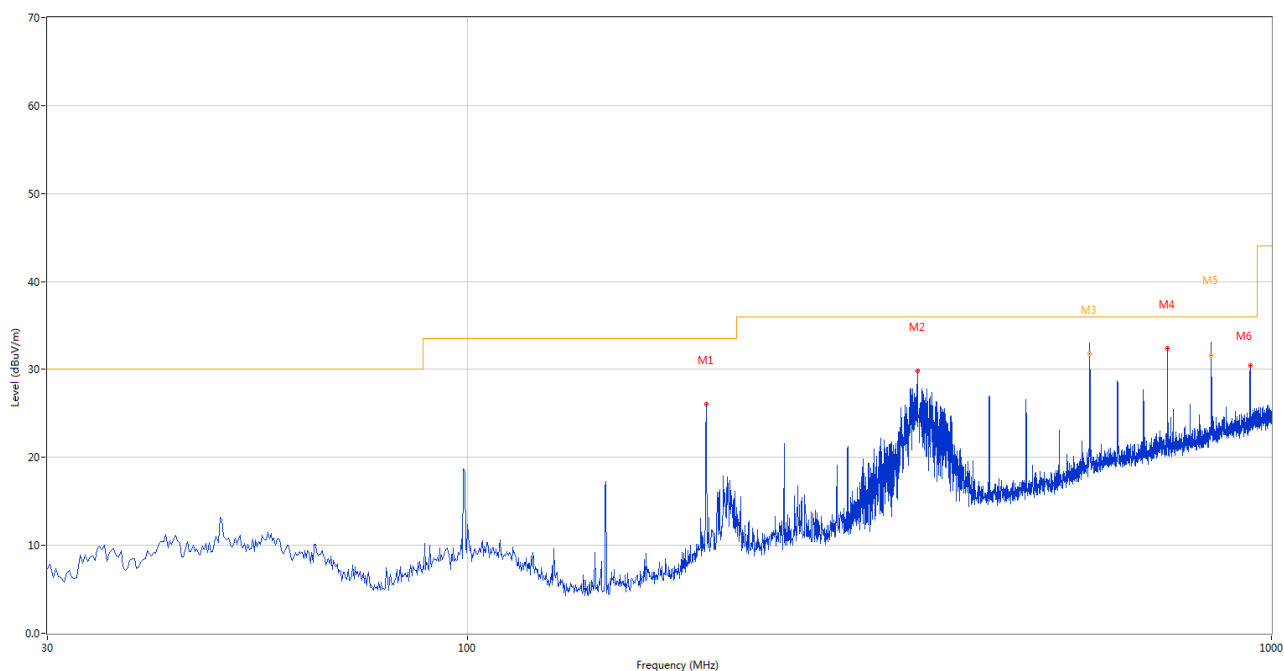
The GSM 850 Test Mode

A.1.1 Test Antenna Vertical, 30 MHz – 1 GHz



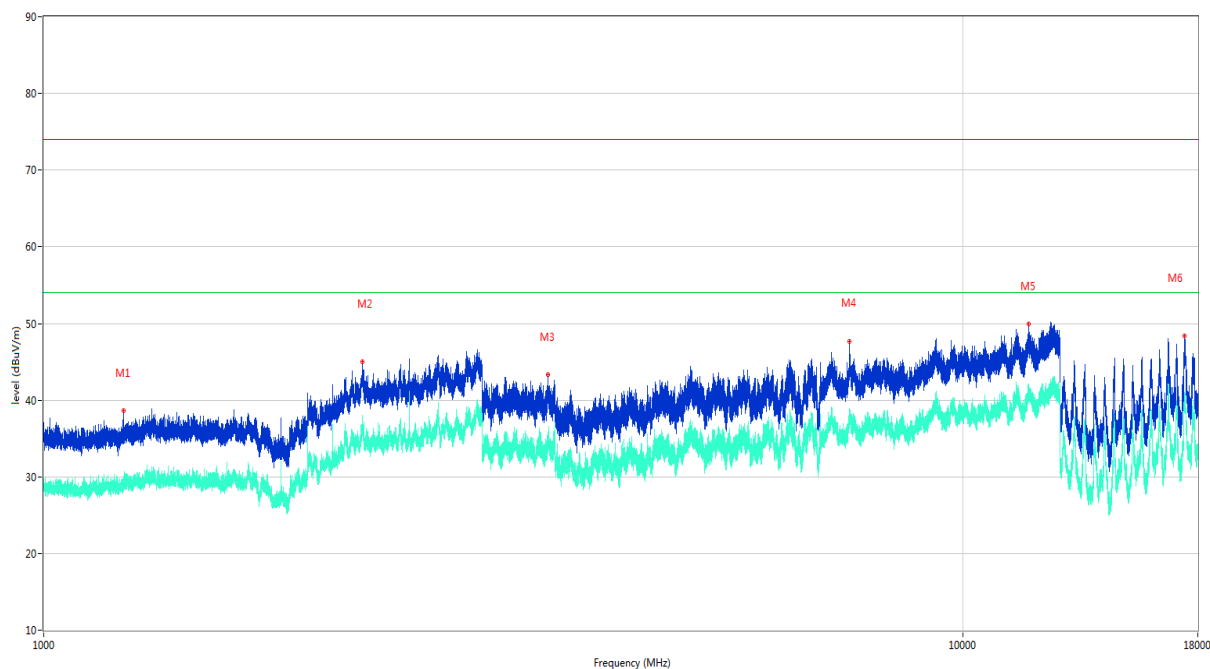
No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	99.095	25.16	-28.07	33.5	8.34	Peak	338.00	100	Vertical	Pass
2	594.399	31.61	-18.11	36.0	4.39	Peak	10.00	200	Vertical	Pass
3	643.614	30.71	-17.26	36.0	5.29	Peak	177.00	200	Vertical	Pass
4	742.772	31.16	-15.32	36.0	4.84	Peak	38.00	200	Vertical	Pass
5	842.031	33.64	-13.79	36.0	2.36	Peak	196.00	200	Vertical	N/A
5*	842.031	31.85	-13.79	36.0	4.15	QP	196.00	200	Vertical	Pass
6	941.033	33.10	-12.10	36.0	2.90	Peak	187.00	186	Vertical	N/A
6*	941.033	30.57	-12.10	36.0	5.43	QP	187.00	186	Vertical	Pass

A.1.2 Test Antenna Horizontal, 30 MHz – 1 GHz



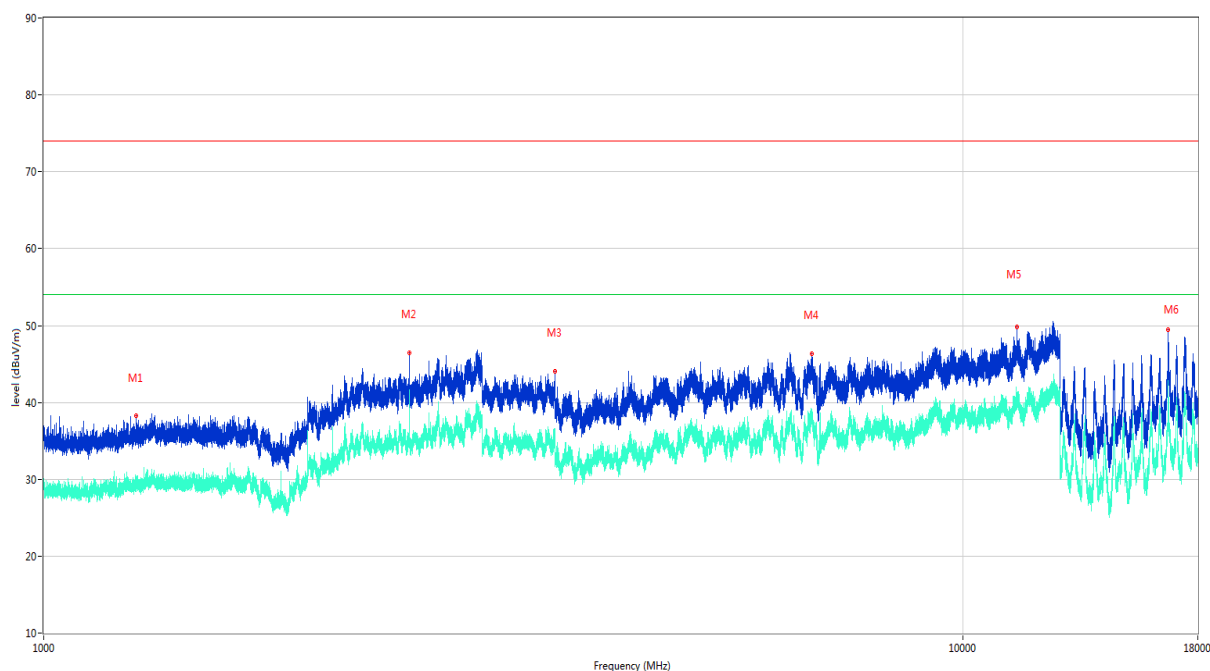
No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Margin (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	198.010	26.02	-27.81	33.5	7.48	Peak	261.00	200	Horizontal	Pass
2	363.112	29.88	-23.44	36.0	6.12	Peak	233.00	200	Horizontal	Pass
3	594.156	33.04	-18.11	36.0	2.96	Peak	189.00	100	Horizontal	N/A
3*	594.156	31.74	-18.11	36.0	4.26	QP	189.00	100	Horizontal	Pass
4	743.014	32.42	-15.33	36.0	3.58	Peak	329.00	100	Horizontal	Pass
5	841.923	33.33	-13.79	36.0	2.67	Peak	239.00	112	Horizontal	N/A
5*	841.923	31.59	-13.79	36.0	4.41	QP	239.00	112	Horizontal	Pass
6	940.602	30.43	-12.04	36.0	5.57	Peak	248.00	100	Horizontal	Pass

A.1.3 Test Antenna Vertical, 1 GHz – 18 GHz



No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Over Limit (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	1222.000	38.65	-15.72	74.0	-35.35	Peak	232.70	100	Vertical	Pass
1**	1222.000	29.50	-15.72	54.0	-24.50	AV	232.70	100	Vertical	Pass
2	2221.900	44.98	-8.39	74.0	-29.02	Peak	303.70	100	Vertical	Pass
2**	2221.900	36.56	-8.39	54.0	-17.44	AV	303.70	100	Vertical	Pass
3	3538.000	43.26	-6.60	74.0	-30.74	Peak	0.00	100	Vertical	Pass
3**	3538.000	34.17	-6.60	54.0	-19.83	AV	0.00	100	Vertical	Pass
4	7524.400	47.63	16.33	74.0	-26.37	Peak	57.10	100	Vertical	Pass
4**	7524.400	37.81	16.33	54.0	-16.19	AV	57.10	100	Vertical	Pass
5	11785.150	49.96	21.52	74.0	-24.04	Peak	152.30	100	Vertical	Pass
5**	11785.150	40.34	21.52	54.0	-13.66	AV	152.30	100	Vertical	Pass
6	17400.187	48.33	24.66	74.0	-25.67	Peak	198.90	100	Vertical	Pass
6**	17400.187	38.95	24.66	54.0	-15.05	AV	198.90	100	Vertical	Pass

A.1.4 Test Antenna Horizontal, 1 GHz – 18 GHz



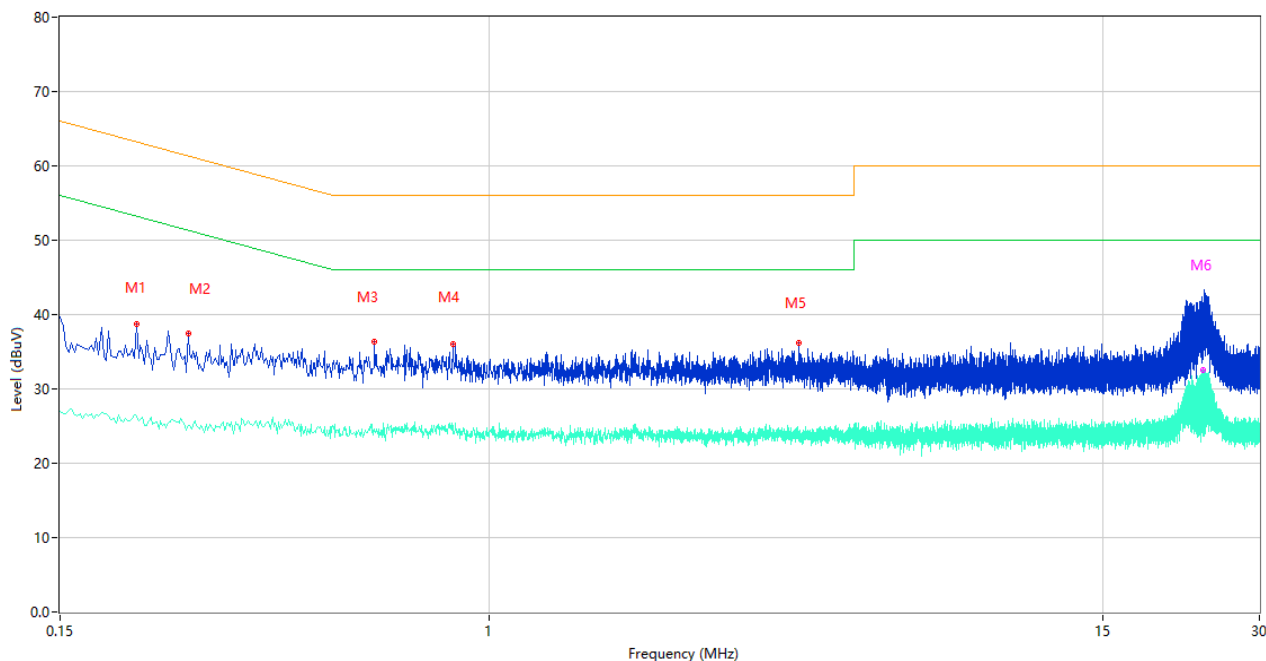
No.	Frequency (MHz)	Results (dBuV/m)	Factor (dB)	Limit (dBuV/m)	Over Limit (dB)	Detector	Table (Degree)	Height (cm)	Antenna	Verdict
1	1259.300	38.23	-15.60	74.0	-35.77	Peak	285.70	100	Horizontal	Pass
1**	1259.300	29.87	-15.60	54.0	-24.13	AV	285.70	100	Horizontal	Pass
2	2500.400	46.41	-9.17	74.0	-27.59	Peak	345.30	100	Horizontal	Pass
2**	2500.400	41.49	-9.17	54.0	-12.51	AV	345.30	100	Horizontal	Pass
3	3598.600	44.07	-5.98	74.0	-29.93	Peak	278.90	100	Horizontal	Pass
3**	3598.600	36.53	-5.98	54.0	-17.47	AV	278.90	100	Horizontal	Pass
4	6849.600	46.31	-2.12	74.0	-27.69	Peak	358.40	100	Horizontal	Pass
4**	6849.600	38.31	-2.12	54.0	-15.69	AV	358.40	100	Horizontal	Pass
5	11450.787	49.77	20.78	74.0	-24.23	Peak	143.00	100	Horizontal	Pass
5**	11450.787	40.09	20.78	54.0	-13.91	AV	143.00	100	Horizontal	Pass
6	16719.000	49.51	25.60	74.0	-24.49	Peak	125.70	100	Horizontal	Pass
6**	16719.000	40.93	25.60	54.0	-13.07	AV	125.70	100	Horizontal	Pass

A.2 Conducted Emission

Test Data and Plots

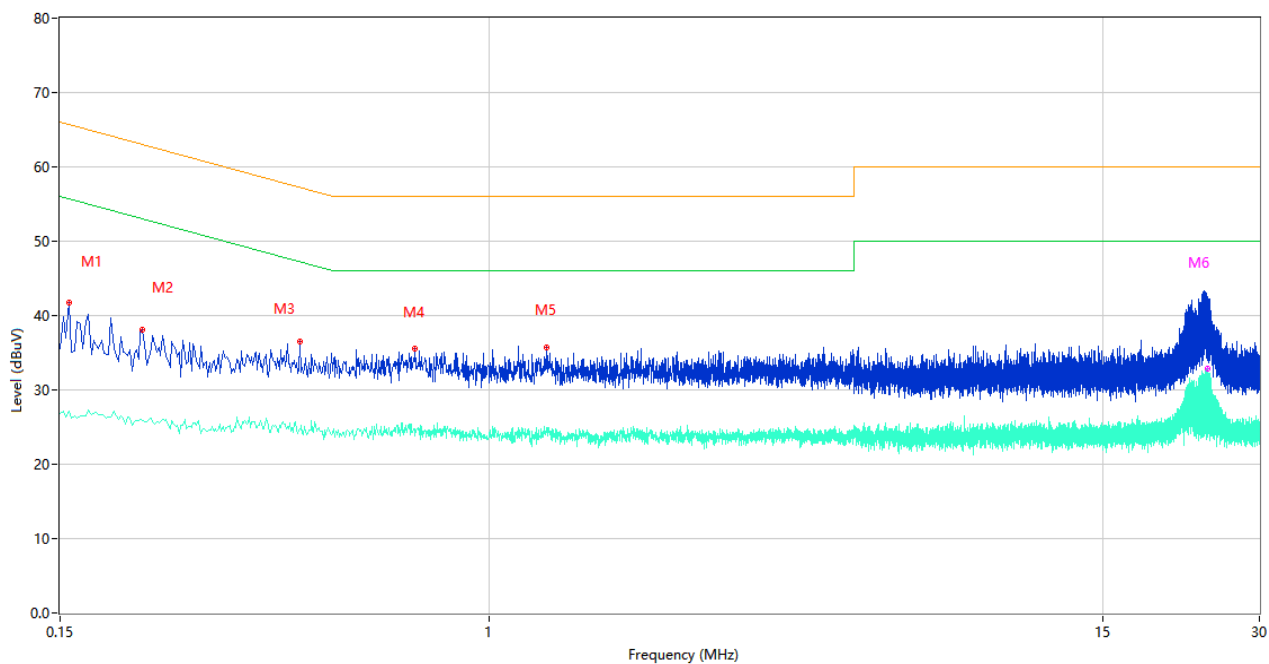
The GSM 850 Test Mode

A.2.1 L Phase



No.	Frequency (MHz)	Results (dBuV)	Factor (dB)	Limit (dBuV)	Margin (dB)	Detector	Line	Verdict
1	0.210	38.71	10.05	63.21	24.50	Peak	L	Pass
1**	0.210	26.34	10.05	53.21	26.87	AV	L	Pass
2	0.264	37.48	10.01	61.30	23.82	Peak	L	Pass
2**	0.264	25.10	10.01	51.30	26.20	AV	L	Pass
3	0.602	36.29	10.34	56.00	19.71	Peak	L	Pass
3**	0.602	24.63	10.34	46.00	21.37	AV	L	Pass
4	0.850	36.07	10.75	56.00	19.93	Peak	L	Pass
4**	0.850	25.13	10.75	46.00	20.87	AV	L	Pass
5	3.928	36.15	10.23	56.00	19.85	Peak	L	Pass
5**	3.928	23.79	10.23	46.00	22.21	AV	L	Pass
6	23.450	41.09	10.45	60.00	18.91	Peak	L	Pass
6**	23.450	32.49	10.45	50.00	17.51	AV	L	Pass

A.2.2 N Phase



No.	Frequency (MHz)	Results (dBuV)	Factor (dB)	Limit (dBuV)	Margin (dB)	Detector	Line	Verdict
1	0.156	41.79	10.09	65.67	23.88	Peak	N	Pass
1**	0.156	27.10	10.09	55.67	28.57	AV	N	Pass
2	0.216	38.15	10.04	62.97	24.82	Peak	N	Pass
2**	0.216	25.93	10.04	52.97	27.04	AV	N	Pass
3	0.432	36.53	10.42	57.21	20.68	Peak	N	Pass
3**	0.432	24.76	10.42	47.21	22.45	AV	N	Pass
4	0.720	35.55	10.61	56.00	20.45	Peak	N	Pass
4**	0.720	23.88	10.61	46.00	22.12	AV	N	Pass
5	1.288	35.73	10.60	56.00	20.27	Peak	N	Pass
5**	1.288	24.97	10.60	46.00	21.03	AV	N	Pass
6	23.872	42.42	10.57	60.00	17.58	Peak	N	Pass
6**	23.872	32.88	10.57	50.00	17.12	AV	N	Pass

ANNEX B TEST SETUP PHOTOS

Please refer the document “BL-EC2350663-AE.PDF”.

ANNEX C EUT EXTERNAL PHOTOS

Please refer the document “BL-EC2350663-AW.PDF”.

ANNEX D EUT INTERNAL PHOTOS

Please refer the document “BL-EC2350663-AI.PDF”.

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